

. 159

. 163

. 71

. 181

. 191

. 199

..209

...223

..229

..241 ..257

..269

..277

..283

..291

Δ

DOCKET

RM

Volume 29 Number 6 June 1998

ISSN 0026-2692

# MICROELECTRONICS M5858 JOURNAL

List of Contents and Author Index for Volume 28, 1997, are inserted loose in this issue

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### CONTENTS

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Refereed Papers
Differential sheet resistivity of mixed implanted (phosphorus + boron) silicon
A. Kumar, G.S. Virdi, P.J. George, S.K. Chattopadhyaya and N. Nath
The VESA generalized timing formula
A. Morrish
A quantitative analysis of wiring lengths in 2D and 3D VLSI
A. Milenkovic and V. Milutinovic
Application of byte error detecting codes to the design of self-checking circuits
S. Pagey and A.J. Al-Khalili
Kinetics of oxidation of copper alloy leadframes
S.K. Lahiri, N.K. Waalib Singh, K.W. Heng, L. Ang and L.C. Goh
Chip on glass—interconnect for row/column driver packaging
R. Joshi
Book Reviews
PatentsALERT





02094



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## Chip on glass—interconnect for row/column driver packaging

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New liquid crystal active matrix color flat panel displays and super twisted nematic liquid crystal displays and other flat panel displays are driving new interconnect technologies to make low cost, thin, compact, mass terminations with high resolution capabilities. Chip on glass (COG) and flip chip on glass (FCOG) are being used to mount the driver IC directly on to the glass LCD. FCOG and COG offer the highest density possible in packaging. Several interconnect technologies in FCOG/ COG have been developed; their strengths and weaknesses are discussed in this paper. The challenges for COG adoption are also discussed. © 1998 Elsevier Science Ltd. All rights reserved.

#### 1. Introduction

T he liquid crystal display (LCD) market can be considered to be a large application of the flip chip market in the form of chip on glass (COG). It is estimated that about 60% of the displays use tape automated bonding (TAB) technology. In Japan, COG is typically used for LCDs that are under 6 inches in size. Figure 1 gives typical adoption rates for COG as a function of the panel size.

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For display driver IC to glass interconnect, a key requirement of the process is that it should be low cost, manufacturable and reworkable.

Several methods have been used historically to interconnect driver ICs to the glass. For example, conventional packages like a thin quad flat package (TQFP) on a printed wiring board, which in turn is connected to the glass using flex. A fine pitch chip on tape package like the tape carrier package (TCP) is also currently used. The outputs of the driver IC on the TCP are connected to the glass using anisotropic conductive epoxy. In COG, the bare (unpackaged) driver ICs are mounted directly on the glass panel. Thus, COG has the potential of using the most simplified assembly process flow and as it does not involve the use of a conventional package (like TCP), it can be a low cost interconnection method.

One method to connect the mounted die is by wire bonding the IC to the metallization on the glass. In this method, the interconnects are made to the metallization one bond pad at a time. This method is also not very efficient in

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supporting high density or fine pitch interconnect, though it is an inexpensive and mature interconnect method in the industry.

An alternative interconnect process is flip chip on glass (FCOG). FCOG is a system level interconnect and should be treated as such.

#### 2. COG

Several methods exist for attaching bare driver ICs on to glass. A review of their technologies along with their key attributes is given in Table 1.

From Table 1 the method that uses modified conventional assembly equipment is stud bumping, which eliminates the need for lithography and associated mask costs. The most common method, however, for COG, is the use of adhesives for accomplishing the interconnect. Figure 2 gives the process flow for these two processes.

Two types of adhesive processes exist: one where the epoxy which facilitates electrical contact between the bump and the trace metallization without itself being in the conduction path, as in UV curable resins, or are in the

Method	Stud Ball	Anisotropic	Micro Bump	Conductive
	Bumps	Conductive	Bonding (UV	Particle
	L	Film (ACF)	Resin)	
	IC Au bump Glass ITO Conductive paste	IC Au bump Conductive particle in ACF	IC Au bump ITO Glass UV Cured resin	Conductive particle
Interconnect	Conductive Paste	ACF	None	Conductive Particle
IC Electrode	Au Ball on Al Pad	Au Bump	Au Bump	Al Pad
Conductor on	ITO	ITO	ITO	ITO
Substrate				
Pitch (µm)	60-130	150-200	50	60-130
	i.	(recent work		
		shown up to 40		
		micron)		
Bond Temperature	100-120 C	160-180 C	room temp	150-200 C
Bond Pressure	1-2 g/pad	20-50 g/pad	10-20 g/pad	10-20 g/pad
Cure Method	Thermal	Thermal	UV	Thermal
Repairability	Poor after	difficult	very difficult	difficult
	underfill			
Benefits	- Flexible		-Low cost	-No bumps
	bumping method		High thru'put	needed
	- low capital			
Drawbacks	-one at a time			-Unreliable
	bumping			connection with
				Al

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